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Collapse Phenomenon in Phase Noise Curve of E5052B

In the experiment of a 10MHz low phase noise crystal oscillator, a collapse phenomenon was ob-served in the phase noise curve when testing with Agilent E5052B. It was believed that this was caused by the instrument's background noise. The numerical relationship of this phenomenon was estimated, and a solution was proposed.

Authors: HUANG, Xianhe (University of Electronic Science and Technology of China); Ms FU, Wei (University of Electronic Science and Technology of China)

Presenter: HUANG, Xianhe (University of Electronic Science and Technology of China)

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